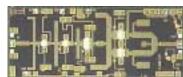
Description

The RMWP38001 is a 4-stage GaAs MMIC amplifier designed as a 37 to 40 GHz Power Amplifier for use in point to point radios, point to multi-point communications, LMDS, and other millimeter wave applications. In conjunction with other Raytheon amplifiers, multipliers and mixers it forms part of a complete 38 GHz transmit/receive chipset. The RMWP38001 utilizes Raytheon's 0.25µm power PHEMT process and is sufficiently versatile to serve in a variety of power amplifier applications.

Features

- 4 mil substrate
- Small-signal gain 22 dB (typ.)
- 1dB compressed Pout 22 dBm (typ.)
- Chip size 3.4 mm x 1.4 mm



Maximum Ratings

<u>Parameter</u>	Symbol	Value	Unit
Positive DC voltage (+4 V Typical)	Vd	+6	Volts
Negative DC voltage	Vg	-2	Volts
Simultaneous (Vd - Vg)	Vdg	8	Volts
Positive DC Current	I _D	483	mΑ
RF Input Power (from 50 Ω source)	P_{IN}	+8	dBm
Operating Baseplate Temperature	T_C	-30 to +85	°C
Storage Temperature Range	T_{stg}	-55 to +125	°C
Thermal Resistance	R_{JC}	46	°C/W
(Channel to Backside)			

Electrical
Characteristics
(At 25°C),
50 Ω system,
Vd=+4 V,
Quiescent
Current
Idq=250 mA

Min	Тур	Max	Unit
37		40	GHz
	-0.5		V
18	22		dB
	4		dB
	21		dB
	22		dBm
21	23.5		dBm
	250		mΑ
	280		mΑ
	270		mΑ
	15		%
	12		dB
	7		dB
	30		dBm
	6		dB
	0.15		V
	37 18	37 -0.5 18 22 4 21 22 21 23.5 250 280 270 15 12 7 30 6	37 40 -0.5 18 22 4 21 22 21 23.5 250 280 270 15 12 7 30 6

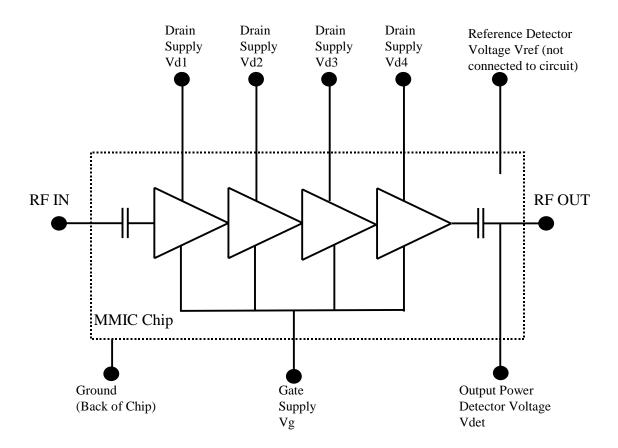
Note 1:

Typical range of gate voltage is -2.0 to 0 V to set Idq of 250 mA.

Raytheon reserves the right to update or change specifications without notice.

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Functional Block Diagram



Note: For output power level detection, bias both detector and reference diodes.

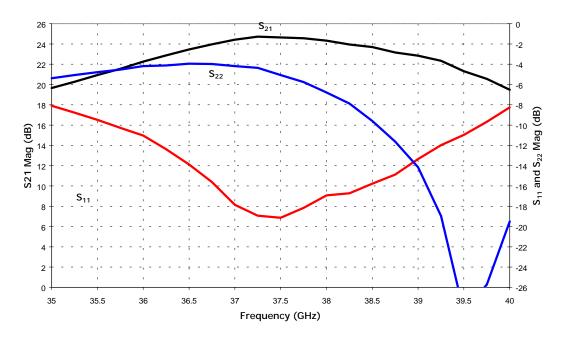
DC voltage difference between detector and reference can be used to measure output power after calibration. If output power level detection is not desired, do not make connection to detector bond pad.

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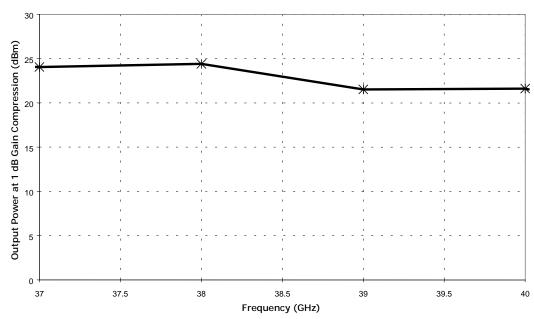
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Performance Data

RMWP38001 38 GHz Power Amplifier Typical On-Wafer Measurements $I_{\text{DQ}} = 250 \text{ mA V}_{\text{DD}} = 4 \text{ V}$



RMWP38001 Typical On-Wafer Output Power at 1 dB Gain Compression Measurements at I $_{DQ}=290~\text{mA}$, $V_{DD}=4.0$



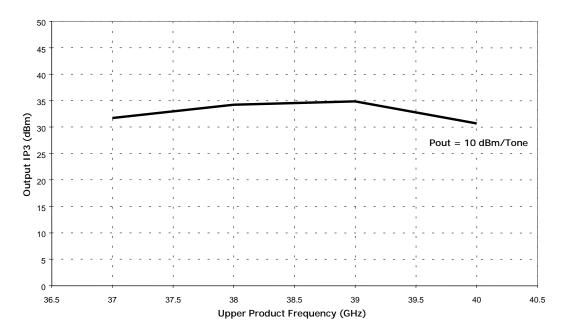
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Performance Data

RMWP38001 38 GHz Power Amplifier. Typical Output IP $_3$ Performance in 50 Ohm Test Fixture. I $_{\rm DQ}=290$ mA,, $_{\rm VD}=4$ V. Tone Spacing = 1 MHz

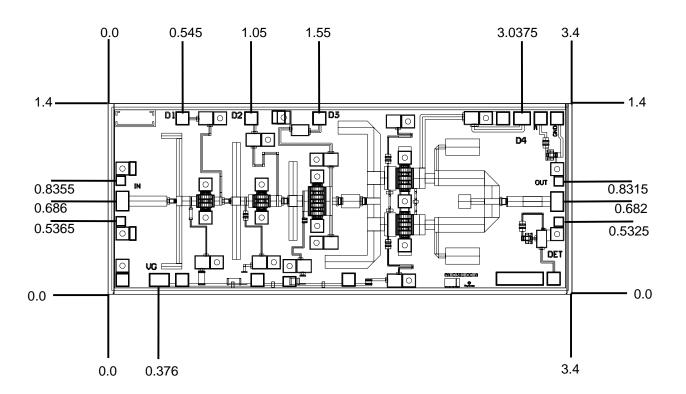


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Application Information

Caution: This is an ESD sensitive device

Chip Layout and Bond Pad Locations
Chip Size is 3.4 mm x 1.4 mm Typical. Back of chip is RF and DC ground



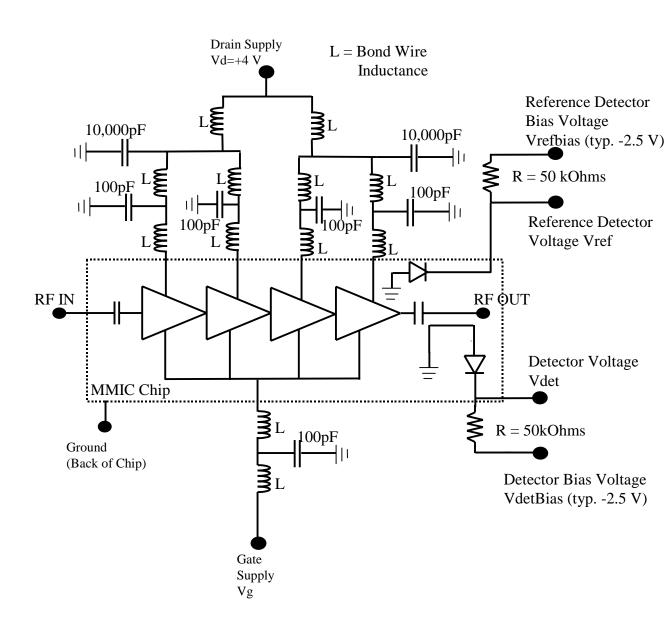
Dimensions in mm

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Application Information

Recommended Application Schematic Circuit Diagram



Note: For output power level detection, bias both detector and reference diodes.

DC voltage difference between detector and reference can be used to measure output power after calibration. If output power level detection is not desired, do not make connection to detector bond pad.

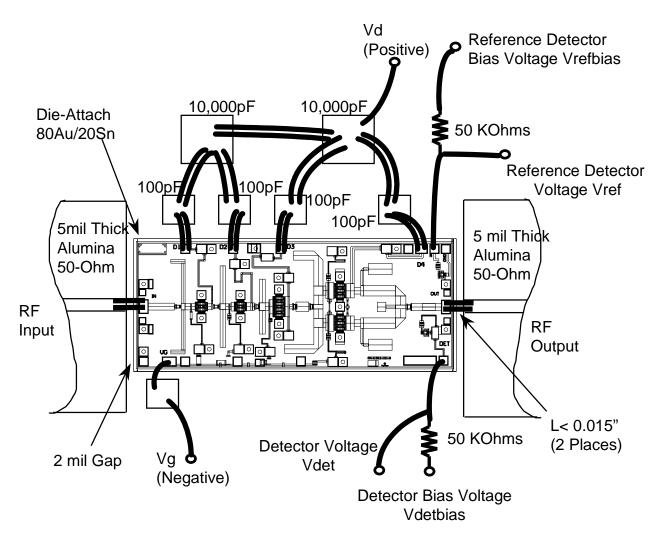
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Application Information

Recommended Assembly Diagram



Note (1): Use 0.003" by 0.0005" Gold Ribbon for bonding. RF input and output bonds should be less than 0.015" long with stress relief.

Note (2): If output power level detection is not desired, do not make connection to detector bond pad.

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Application Information

CAUTION: THIS IS AN ESD SENSITIVE DEVICE.

Chip carrier material should be selected to have GaAs compatible thermal coefficient of expansion and high thermal conductivity such as copper molybdenum or copper tungsten. The chip carrier should be machined, finished flat, plated with gold over nickel and should be capable of withstanding 325°C for 15 minutes.

Die attachment should utilize Gold/Tin (80/20) eutectic alloy solder and should avoid hydrogen environment for PHEMT devices. Note that the backside of the chip is gold plated and is used as RF and DC ground.

These GaAs devices should be handled with care and stored in dry nitrogen environment to prevent contamination of bonding surfaces. These are ESD sensitive devices and should be handled with appropriate precaution including the use of wrist grounding straps. All die attach and wire/ribbon bond equipment must be well grounded to prevent static discharges through the device.

Recommended wire bonding uses 3 mils wide and 0.5 mil thick gold ribbon with lengths as short as practical allowing for appropriate stress relief. The RF input and output bonds should be typically 0.012" long corresponding to a typically 2 mil between the chip and the substrate material.

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Application Information

Recommended Procedure for Biasing and Operation

Caution: This is an ESD sensitive device

Caution: Loss of gate voltage (Vgs) while drain voltage (Vds) is present may damage the amplifier chip.

The following sequence of steps must be followed to properly test the amplifier:

Step 1: Turn off RF input power.

Step 2: Connect the DC supply grounds to the grounds of the chip carrier.

Slowly apply negative gate bias supply voltage of -1.5 V to Vgs.

Step 3: Slowly apply positive drain bias supply voltage of +4 V to Vds.

Step 4: Adjust gate bias voltage to set the quiescent current of Idq=250 mA.

Step 5: After the bias condition is established, RF input signal may now be applied at the

appropriate frequency band.

Step 6: Follow turn-off sequence of:

(i) Turn off RF input power, (ii) Turn down and off drain voltage (Vds), (iii) Turn

down and off gate bias voltage (Vgs).

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